

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-021001	Application No. 09/809,646
	Applicant Shunpei YAMAZAKI et al.		
	Filing Date March 16, 2001	Group Art Unit 2871	

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>YAS</i>	AA	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
<i>YAS</i>	AB	5,923,962	07/13/1999	Ohtani et al.			04/28/1995
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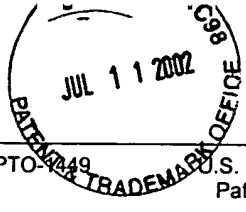
Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>YAS</i>	AL	07-130652	05/19/1995	Japan	H01L	21/20	Abst	
<i>YAS</i>	AM	08-78329	03/22/1996	Japan	H01L	21/20	Abst	
<i>YAS</i>	AN	10-135468	05/22/1998	Japan	H01L	29/786	Abst	
<i>YAS</i>	AO	10-135469	05/22/1998	Japan	H01L	29/786	Abst	
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>YAS</i>	AQ	Hatano et al.; "A Novel Self-aligned Gate-overlapped LDD Poly-Si TFT with High Reliability and Performance"; <i>IEDM Technical Digest 97</i> ; pp. 523-526; 1997
	AR	
	AS	
	AT	

Examiner Signature <i>Yasumasa</i>	Date Considered 05/12/03
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



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							Yes	No
<i>Sub</i>	AL	6-148685	05/27/1994	Japan			Full	
<i>Sub</i>	AM	7-235680	09/05/1995	Japan			Full	
<i>Sub</i>	AN	8-274336	10/18/1996	Japan			Full	
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	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

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Examiner Signature <i>Shunpei Yamazaki</i>	Date Considered <i>5/12/03</i>
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
Jrd	AA	5,767,530	06/16/1998	Ha			09/26/1997
Jrd	AB	6,259,138	07/10/2001	Ohtani et al.			12/16/1999
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							Yes	No
Jrd	AL	EP 1 031 873 A2	08/30/2000	Europe				
Jrd	AM	11-274502	10/08/1999	Japan			ABS	
	AN							
	AO							
	AP							

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